Abstract

X-ray examination apparatus with x-ray image sensor matrix and correction unit.

An x-ray examination apparatus comprises an x-ray image sensor matrix (1) for deriving an initial image signal from the x-ray image. The sensor elements of the x-ray sensor matrix convert incident x-rays into electric charges. These electric charges are read-out and converted into the initial image signal. Further a correction unit (2) is provided for correcting the initial image signal, notably for disturbances due to delayed transferred charges, that have been retained in the sensor elements for some time. The correction unit (2) is provided with a memory which stores correction values. Further the correction provided with a selection unit (5) for selecting appropriate correction values from the memory (3).

Figure 1